

FIG.1(Prior Art)

87.168

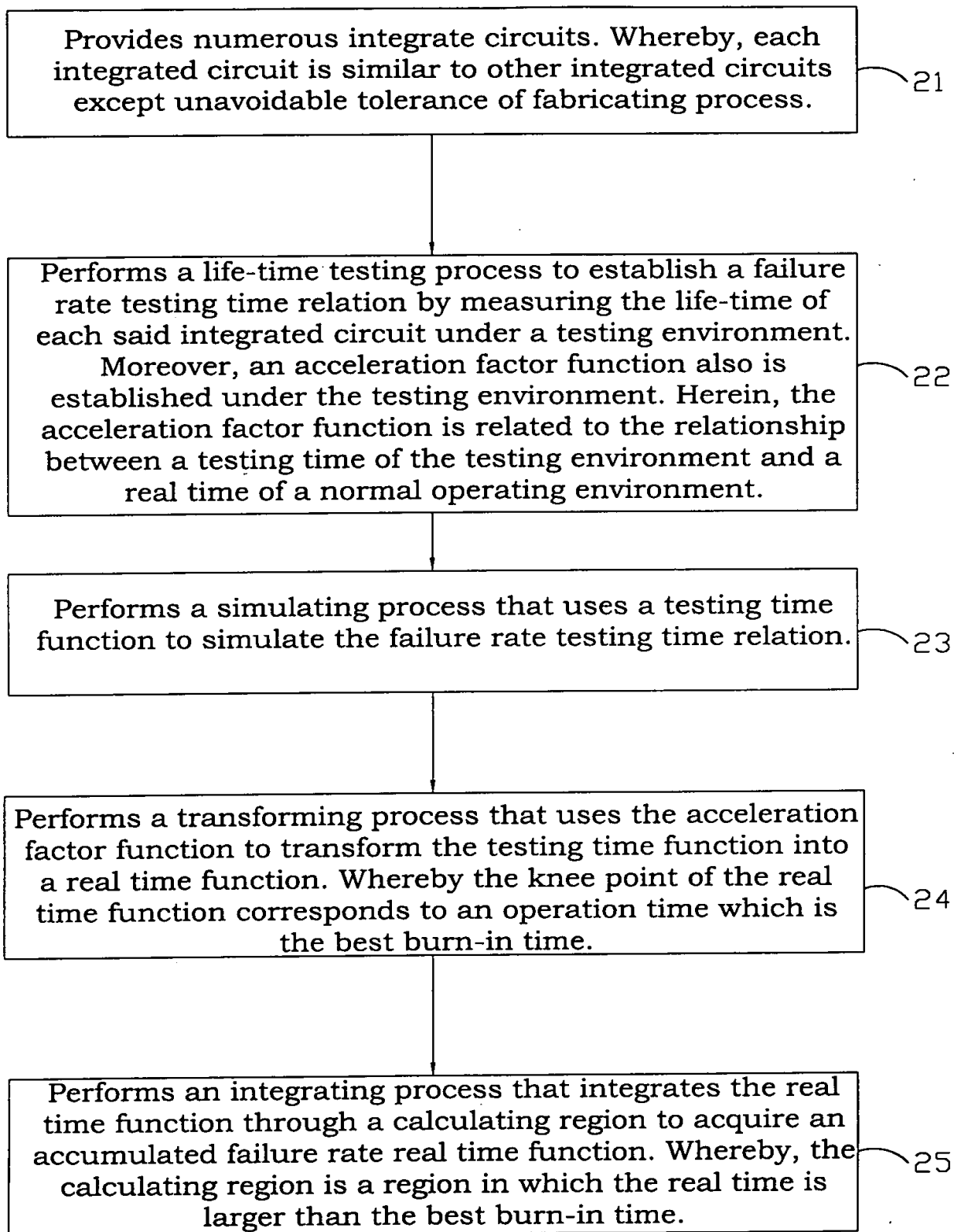


FIG.2

Provides numerous integrate circuits.

31

Performs a life-time testing process to establish a failure rate testing time relation by measuring the life-time of each said integrated circuit under a testing environment. Moreover, an acceleration factor function also is established under the testing environment. Herein, the acceleration factor function is related to the relationship between a testing time of the testing environment and a real time of a normal operating environment.

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Performs a transforming process by using the acceleration factor function to transform the failure rate testing time function into a failure rate real time function.

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Performs a simulating process that uses a real time function to simulate the failure rate real time relation. Whereby, a knee point of the real time function corresponds to an operation time which is the best burn-in time for testing these integrated circuits.

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Performs an integrating process that integrates the real time function through a calculating region to acquire an accumulated failure rate real time function. Whereby, the calculating region is a region in which the real time is larger than the best burn-in time.

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FIG.3

Failure rate  
/Hour

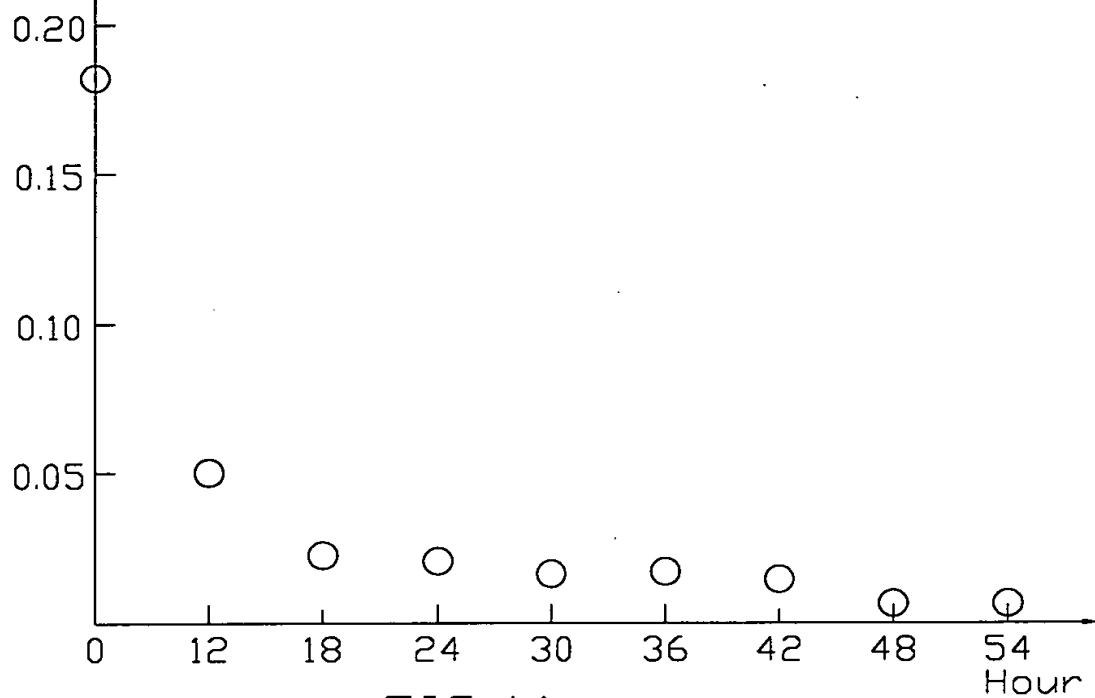


FIG. 4A

Failure rate  
/Hour

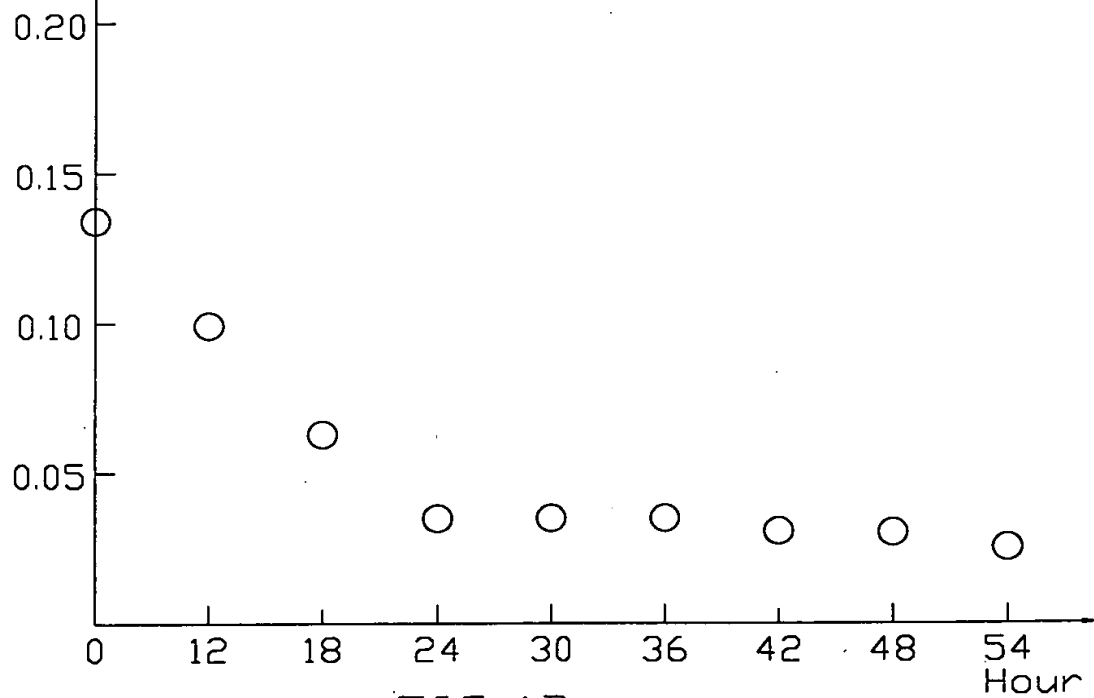


FIG. 4B

Failure rate  
/Hour

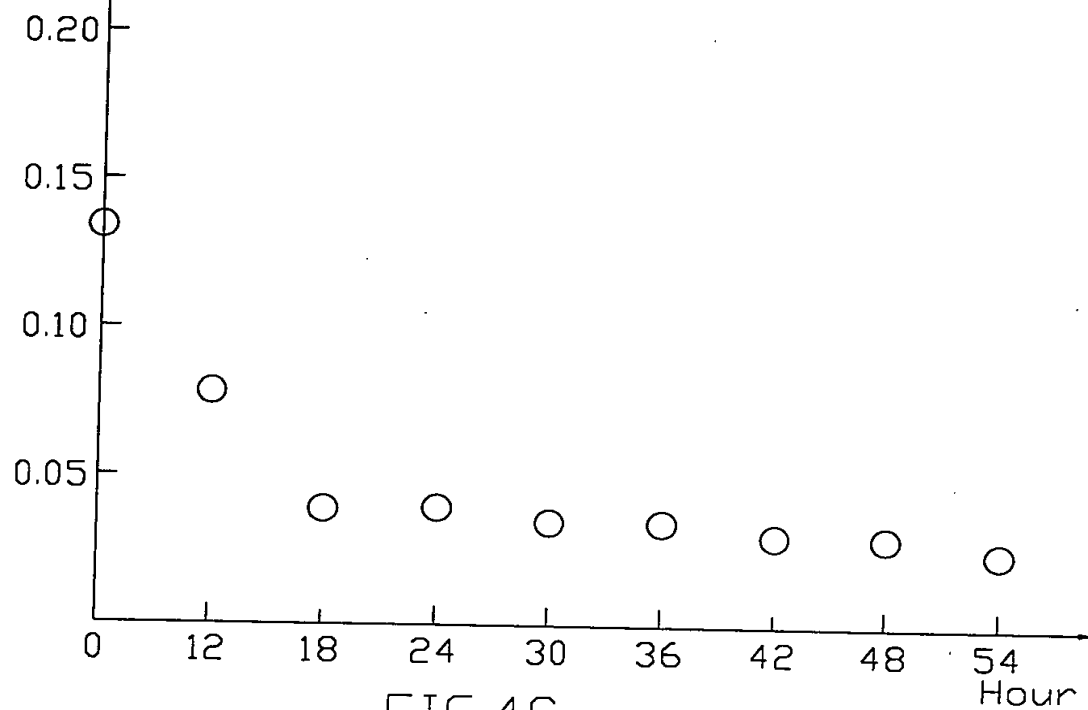


FIG.4C